



PTO-1449		Application No. 09/997,786		Applicant(s) Duncan M. Walker, et al.			
Information Disclosure Citation in an Application		Docket Number 017575.0551		Group Art Unit 2829	Filing Date 11/30/2001		
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2B	B	5,570,034	10/29/1996	Needham et al.	324	763	12/29/1994
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	F	P. Nigh, W. Needham, K. Butler, P. Maxwell and R. Aitken, "An Experimental Study Comparing the Relative Effectiveness of Functional, Scan, IDDq and Delay-fault Testing, <u>IEEE Int'l ASIC Conference</u>					1996
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	H	J.M. Soden and C.F Hawkins, "IDDQ Testing and Defect Classes - A Tutorial," <u>IEEE Custom Integrated Circuits Conference</u>					1995
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	Q	A.D. Singh, "Experiments with an On-Chip IDDQ Current Sensor for VLSI Testing," <u>IEEE Int'l Workshop on IDDQ Testing</u>			1995
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